

Notice of References Cited	Application/Control No. 10/524,715		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner HAI V. NGUYEN		Art Unit 2618	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0174678 A1	09-2003	Chang et al.	370/335
*	B	US-2004/0105402 A1	06-2004	Yi et al.	370/312
*	C	US-2008/0049697 A1	02-2008	Breuer et al.	370/341
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	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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